Search Notes

Application/Control	No.	

Applicant(s)/Patent	und	er
Reexamination		

10/624,173

Examiner

Devin Hanan

BAUMANN ET AL.
Art Unit

Examiner

3745

	SEARCHED		
Class ·	Subclass	Date	Examiner
415	202,203		
416	185,186R	2/2/2007	DH
	,		
		,	
			"
•			
			_

INI	INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner	
				
:				

SEARCH (INCLUDING SEAF	NOTES RCH STRATEGY	')
	DATE	EXMR
consulted Ninh Nguyen on class 415 and 416	1/25/2007	DH
	:	